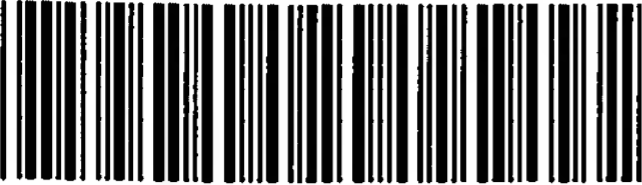


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/625,209	LEE ET AL.	
	Examiner	Art Unit	
	Mark A. Mais	2616	

SEARCHED			
Class	Subclass	Date	Examiner
370	310 316	3/18/2007	MAM
	319-322		
	328 395.1		
	395.21		
	395.4		
	395.41		
	395.42		
	431		
455	12.1 427		
	430		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
See Inventorship Search	3/18/2007	MAM
See Attached electronic Search	3/18/2007	MAM